

DATA SHEET

BF1201; BF1201R; BF1201WR N-channel dual-gate PoLo MOS-FETs

Product specification
Supersedes data of 1999 Dec 01

2000 Mar 29

N-channel dual-gate PoLo MOS-FETs

BF1201; BF1201R;
BF1201WR

FEATURES

- Short channel transistor with high forward transfer admittance to input capacitance ratio
- Low noise gain controlled amplifier
- Partly internal self-biasing circuit to ensure good cross-modulation performance during AGC and good DC stabilization.

APPLICATIONS

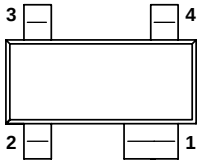
- VHF and UHF applications with 3 to 9 V supply voltage, such as digital and analogue television tuners and professional communications equipment.

DESCRIPTION

Enhancement type N-channel field-effect transistor with source and substrate interconnected. Integrated diodes between gates and source protect against excessive input voltage surges. The BF1201, BF1201R and BF1201WR are encapsulated in the SOT143B, SOT143R and SOT343R plastic packages respectively.

PINNING

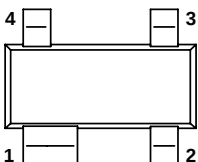
PIN	DESCRIPTION
1	source
2	drain
3	gate 2
4	gate 1



Top view MSB035

BF1201R marking code: LBp

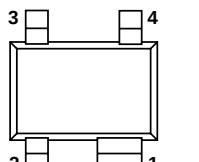
Fig.2 Simplified outline (SOT143R).



Top view MSB014

BF1201 marking code: LAp.

Fig.1 Simplified outline (SOT143B).



Top view MSB842

BF1201WR marking code: LA

Fig.3 Simplified outline (SOT343R).

QUICK REFERENCE DATA

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
V_{DS}	drain-source voltage		–	–	10	V
I_D	drain current		–	–	30	mA
P_{tot}	total power dissipation		–	–	200	mW
$ y_{fs} $	forward transfer admittance		23	28	35	mS
C_{ig1-ss}	input capacitance at gate 1		–	2.6	3.1	pF
C_{rss}	reverse transfer capacitance	$f = 1\text{ MHz}$	–	15	30	fF
F	noise figure	$f = 400\text{ MHz}$	–	1	1.8	dB
X_{mod}	cross-modulation	input level for $k = 1\%$ at 40 dB AGC	105	–	–	dB μ V
T_j	operating junction temperature		–	–	150	°C

CAUTION

This product is supplied in anti-static packing to prevent damage caused by electrostatic discharge during transport and handling. For further information, refer to Philips specs.: SNW-EQ-608, SNW-FQ-302A and SNW-FQ-302B.

N-channel dual-gate PoLo MOS-FETs

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BF1201WR

LIMITING VALUES

In accordance with the Absolute Maximum Rating System (IEC 60134).

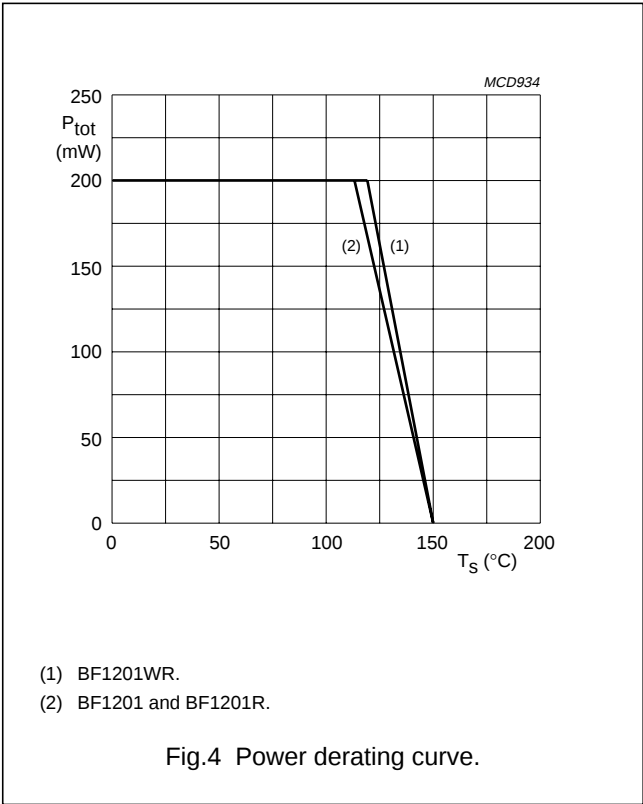
SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V _{DS}	drain-source voltage		–	10	V
I _D	drain current (DC)		–	30	mA
I _{G1}	gate 1 current		–	±10	mA
I _{G2}	gate 2 current		–	±10	mA
P _{tot}	total power dissipation				
	BF1201; BF1201R	T _s ≤ 113 °C; note 1	–	200	mW
	BF1201WR	T _s ≤ 109 °C; note 1	–	200	mW
T _{stg}	storage temperature		–65	+150	°C
T _j	operating junction temperature		–	150	°C

Note

1. T_s is the temperature of the soldering point of the source lead.

THERMAL CHARACTERISTICS

SYMBOL	PARAMETER	VALUE	UNIT
R _{th j-s}	thermal resistance from junction to soldering point		
	BF1201; BF1201R	185	K/W
	BF1201WR	155	K/W



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STATIC CHARACTERISTICS

 $T_j = 25\text{ }^{\circ}\text{C}$; unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
$V_{(BR)DSS}$	drain-source breakdown voltage	$V_{G1-S} = V_{G2-S} = 0$; $I_D = 10\text{ }\mu\text{A}$	10	–	V
$V_{(BR)G1-SS}$	gate 1-source breakdown voltage	$V_{G2-S} = V_{DS} = 0$; $I_{G1-S} = 10\text{ mA}$	6	–	V
$V_{(BR)G2-SS}$	gate 2-source breakdown voltage	$V_{G1-S} = V_{DS} = 0$; $I_{G2-S} = 10\text{ mA}$	6	–	V
$V_{(F)S-G1}$	forward source-gate 1 voltage	$V_{G2-S} = V_{DS} = 0$; $I_{S-G1} = 10\text{ mA}$	0.5	1.5	V
$V_{(F)S-G2}$	forward source-gate 2 voltage	$V_{G1-S} = V_{DS} = 0$; $I_{S-G2} = 10\text{ mA}$	0.5	1.5	V
$V_{G1-S(th)}$	gate 1-source threshold voltage	$V_{G2-S} = 4\text{ V}$; $V_{DS} = 5\text{ V}$; $I_D = 100\text{ }\mu\text{A}$	0.3	1.0	V
$V_{G2-S(th)}$	gate 2-source threshold voltage	$V_{G1-S} = V_{DS} = 5\text{ V}$; $I_D = 100\text{ }\mu\text{A}$	0.3	1.2	V
I_{DSX}	drain-source current	$V_{G2-S} = 4\text{ V}$; $V_{DS} = 5\text{ V}$; $R_{G1} = 62\text{ k}\Omega$; note 1	11	19	mA
I_{G1-SS}	gate 1 cut-off current	$V_{G2-S} = V_{DS} = 0$; $V_{G1-S} = 5\text{ V}$	–	50	nA
I_{G2-SS}	gate 2 cut-off current	$V_{G1-S} = V_{DS} = 0$; $V_{G2-S} = 4\text{ V}$	–	20	nA

Note

1. R_{G1} connects G_1 to $V_{GG} = 5\text{ V}$.

DYNAMIC CHARACTERISTICS

Common source; $T_{amb} = 25\text{ }^{\circ}\text{C}$; $V_{G2-S} = 4\text{ V}$; $V_{DS} = 5\text{ V}$; $I_D = 15\text{ mA}$; unless otherwise specified.

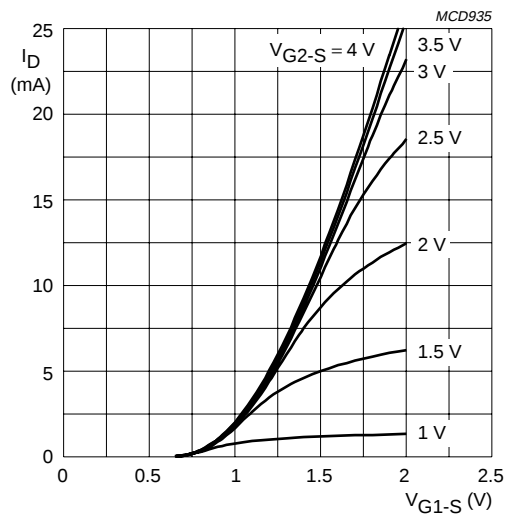
SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$ y_{fs} $	forward transfer admittance	pulsed; $T_j = 25\text{ }^{\circ}\text{C}$	23	28	35	mS
C_{ig1-ss}	input capacitance at gate 1	$f = 1\text{ MHz}$	–	2.6	3.1	pF
C_{ig2-ss}	input capacitance at gate 2	$f = 1\text{ MHz}$	–	1.1	–	pF
C_{oss}	output capacitance	$f = 1\text{ MHz}$	–	0.9	–	pF
C_{rss}	reverse transfer capacitance	$f = 1\text{ MHz}$	–	15	30	fF
F	noise figure	$f = 10.7\text{ MHz}$; $G_S = 20\text{ mS}$; $B_S = 0$	–	5	7	dB
		$f = 400\text{ MHz}$; $Y_S = Y_{S\text{ opt}}$	–	1	1.8	dB
		$f = 800\text{ MHz}$; $Y_S = Y_{S\text{ opt}}$	–	1.9	2.5	dB
G_{tr}	power gain	$f = 200\text{ MHz}$; $G_S = 2\text{ mS}$; $B_S = B_{S\text{ opt}}$; $G_L = 0.5\text{ mS}$; $B_L = B_{L\text{ opt}}$	–	33.5	–	dB
		$f = 400\text{ MHz}$; $G_S = 2\text{ mS}$; $B_S = B_{S\text{ opt}}$; $G_L = 1\text{ mS}$; $B_L = B_{L\text{ opt}}$	–	29	–	dB
		$f = 800\text{ MHz}$; $G_S = 3.3\text{ mS}$; $B_S = B_{S\text{ opt}}$; $G_L = 1\text{ mS}$; $B_L = B_{L\text{ opt}}$	–	24	–	dB
X_{mod}	cross-modulation	input level for $k = 1\%$; $f_w = 50\text{ MHz}$; $f_{unw} = 60\text{ MHz}$; note 1				
		at 0 dB AGC	90	–	–	dB μ V
		at 10 dB AGC	–	95	–	dB μ V
		at 40 dB AGC	105	–	–	dB μ V

Note

1. Measured in Fig.21 test circuit.

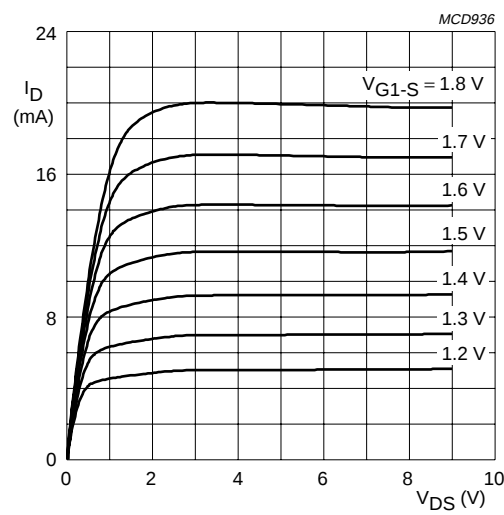
N-channel dual-gate PoLo MOS-FETs

BF1201; BF1201R;
BF1201WR



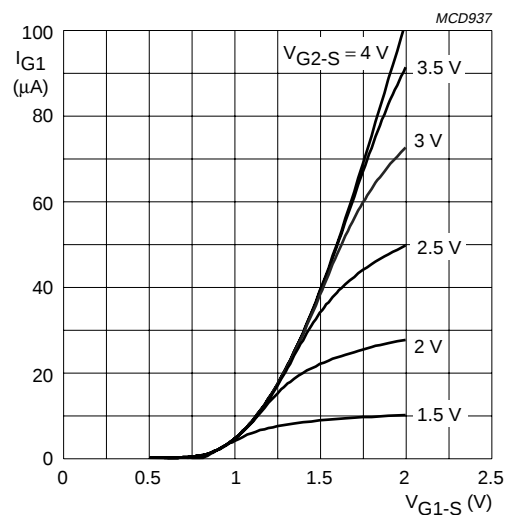
$V_{DS} = 5\text{ V.}$
 $T_j = 25\text{ }^{\circ}\text{C.}$

Fig.5 Transfer characteristics; typical values.



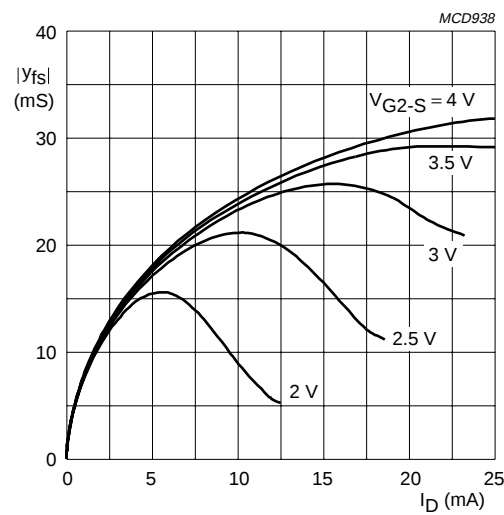
$V_{G2-S} = 4\text{ V.}$
 $T_j = 25\text{ }^{\circ}\text{C.}$

Fig.6 Output characteristics; typical values.



$V_{DS} = 5\text{ V.}$
 $T_j = 25\text{ }^{\circ}\text{C.}$

Fig.7 Gate 1 current as a function of gate 1 voltage; typical values.

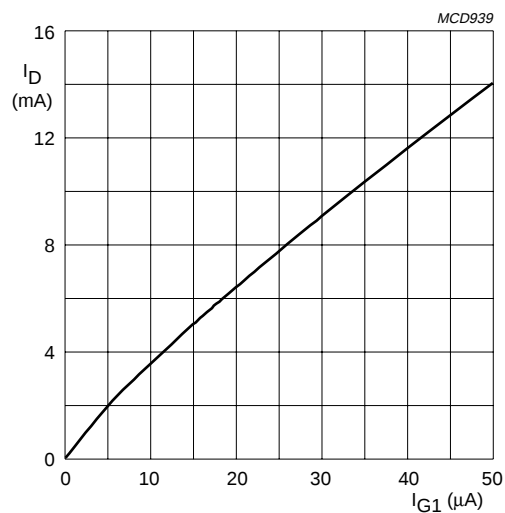


$V_{DS} = 5\text{ V.}$
 $T_j = 25\text{ }^{\circ}\text{C.}$

Fig.8 Forward transfer admittance as a function of drain current; typical values.

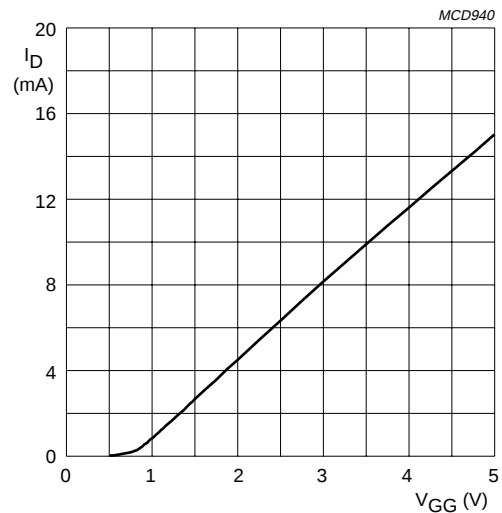
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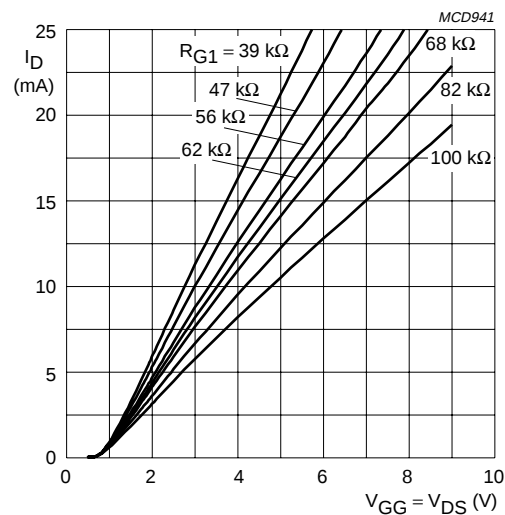
$V_{DS} = 5\text{ V}$; $V_{G2-S} = 4\text{ V}$.
 $T_j = 25\text{ }^{\circ}\text{C}$.

Fig.9 Drain current as a function of gate 1 current; typical values.



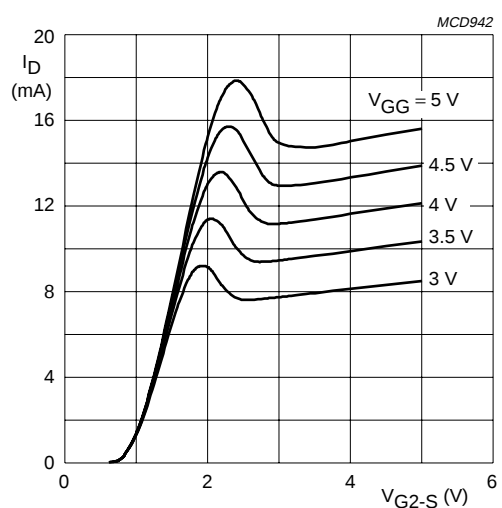
$V_{DS} = 5\text{ V}$; $V_{G2-S} = 4\text{ V}$; $T_j = 25\text{ }^{\circ}\text{C}$.
 $R_{G1} = 62\text{ k}\Omega$ (connected to V_{GG}); see Fig.21.

Fig.10 Drain current as a function of gate 1 supply voltage ($= V_{GG}$); typical values.



$V_{G2-S} = 4\text{ V}$; $T_j = 25\text{ }^{\circ}\text{C}$.
 R_{G1} connected to V_{GG} ; see Fig.21.

Fig.11 Drain current as a function of gate 1 ($= V_{GG}$) and drain supply voltage; typical values.

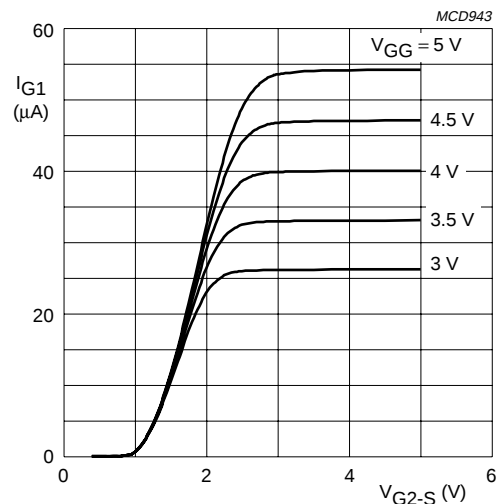


$V_{DS} = 5\text{ V}$; $T_j = 25\text{ }^{\circ}\text{C}$.
 $R_{G1} = 62\text{ k}\Omega$ (connected to V_{GG}); see Fig.21.

Fig.12 Drain current as a function of gate 2 voltage; typical values.

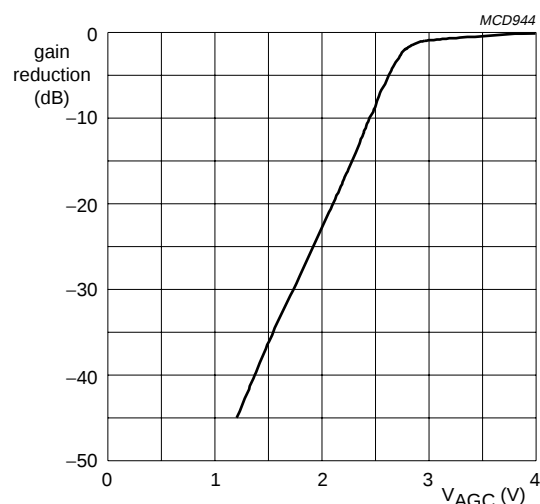
N-channel dual-gate PoLo MOS-FETs

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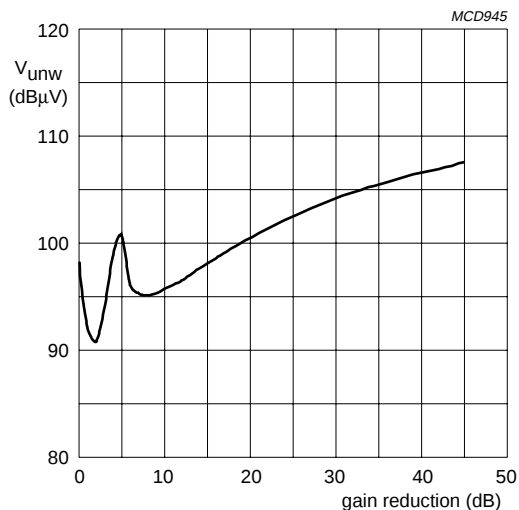
$V_{DS} = 5\text{ V}$; $T_j = 25\text{ }^{\circ}\text{C}$.
 $R_{G1} = 62\text{ k}\Omega$ (connected to V_{GG}); see Fig.21.

Fig.13 Gate 1 current as a function of gate 2 voltage; typical values.



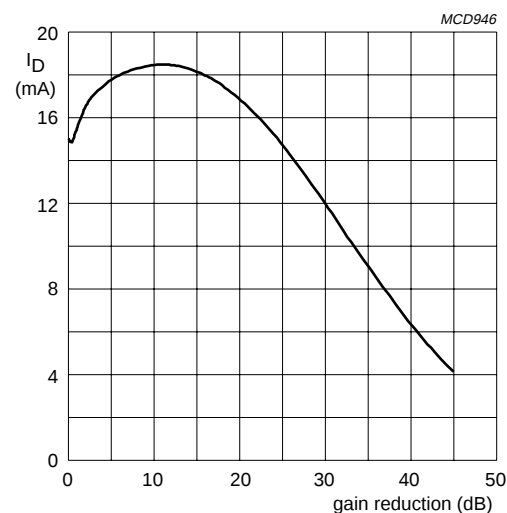
$V_{DS} = 5\text{ V}$; $V_{GG} = 5\text{ V}$; $R_{G1} = 62\text{ k}\Omega$;
 $f = 50\text{ MHz}$; $T_{amb} = 25\text{ }^{\circ}\text{C}$.

Fig.14 Typical gain reduction as a function of the AGC voltage; see Fig.21.



$V_{DS} = 5\text{ V}$; $V_{GG} = 5\text{ V}$; $R_{G1} = 62\text{ k}\Omega$; $f = 50\text{ MHz}$;
 $f_{unw} = 60\text{ MHz}$; $T_{amb} = 25\text{ }^{\circ}\text{C}$.

Fig.15 Unwanted voltage for 1% cross-modulation as a function of gain reduction; typical values; see Fig.21.

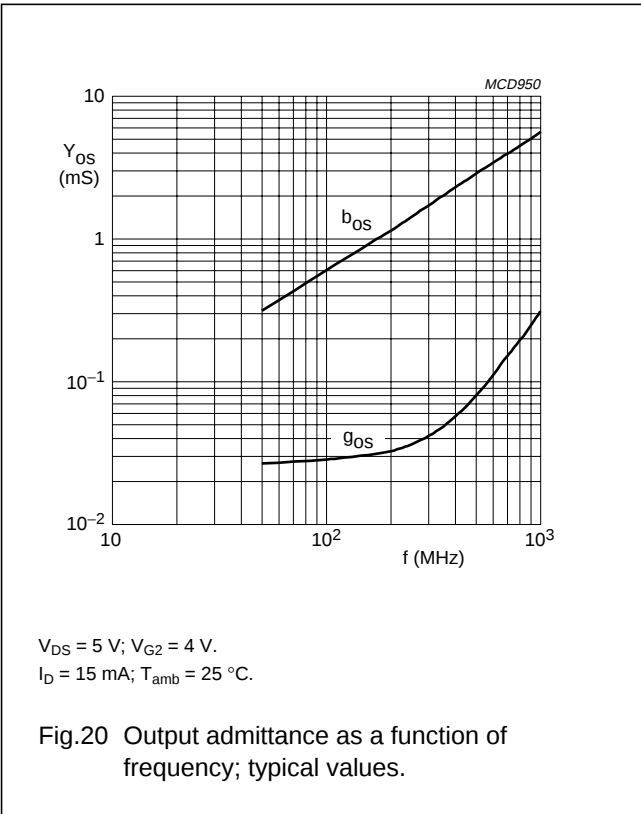
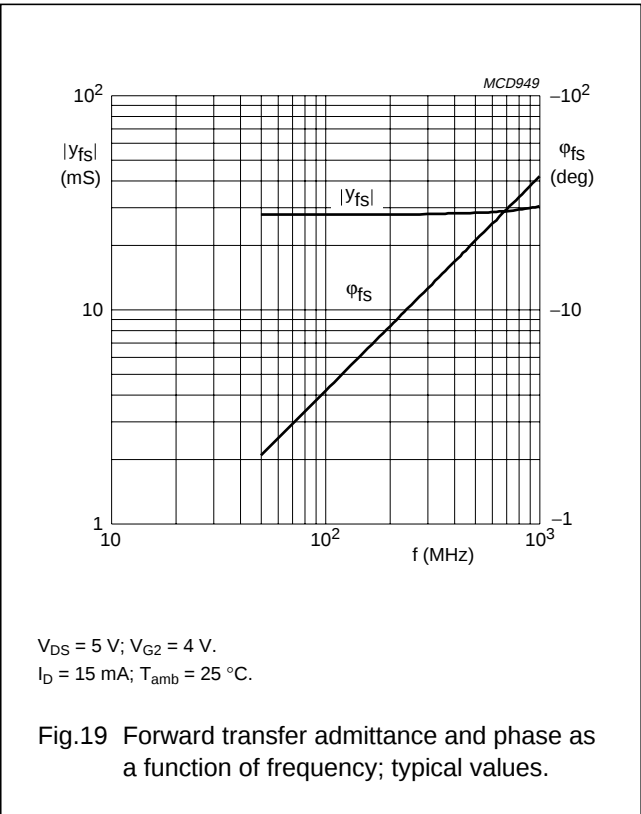
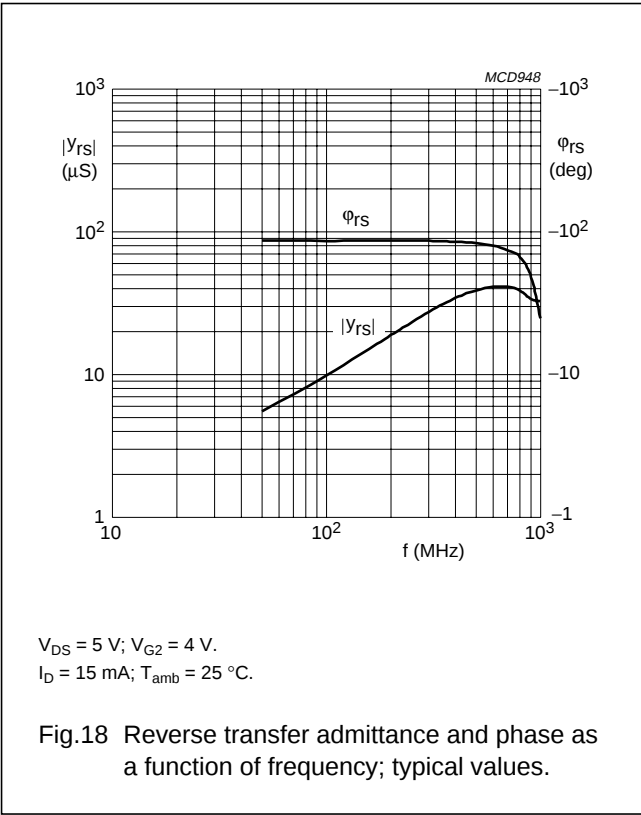
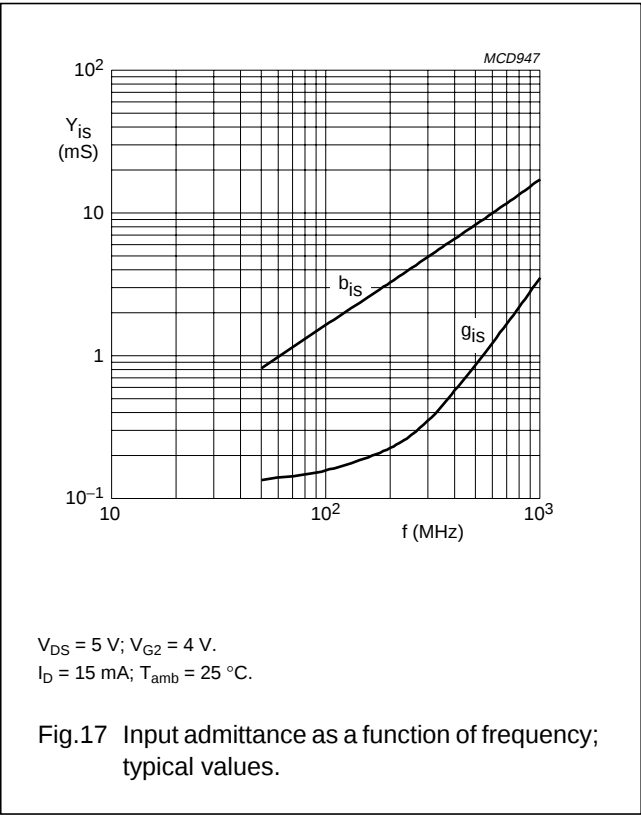


$V_{DS} = 5\text{ V}$; $V_{GG} = 5\text{ V}$; $R_{G1} = 62\text{ k}\Omega$;
 $f = 50\text{ MHz}$; $T_{amb} = 25\text{ }^{\circ}\text{C}$.

Fig.16 Drain current as a function of gain reduction; typical values; see Fig.21.

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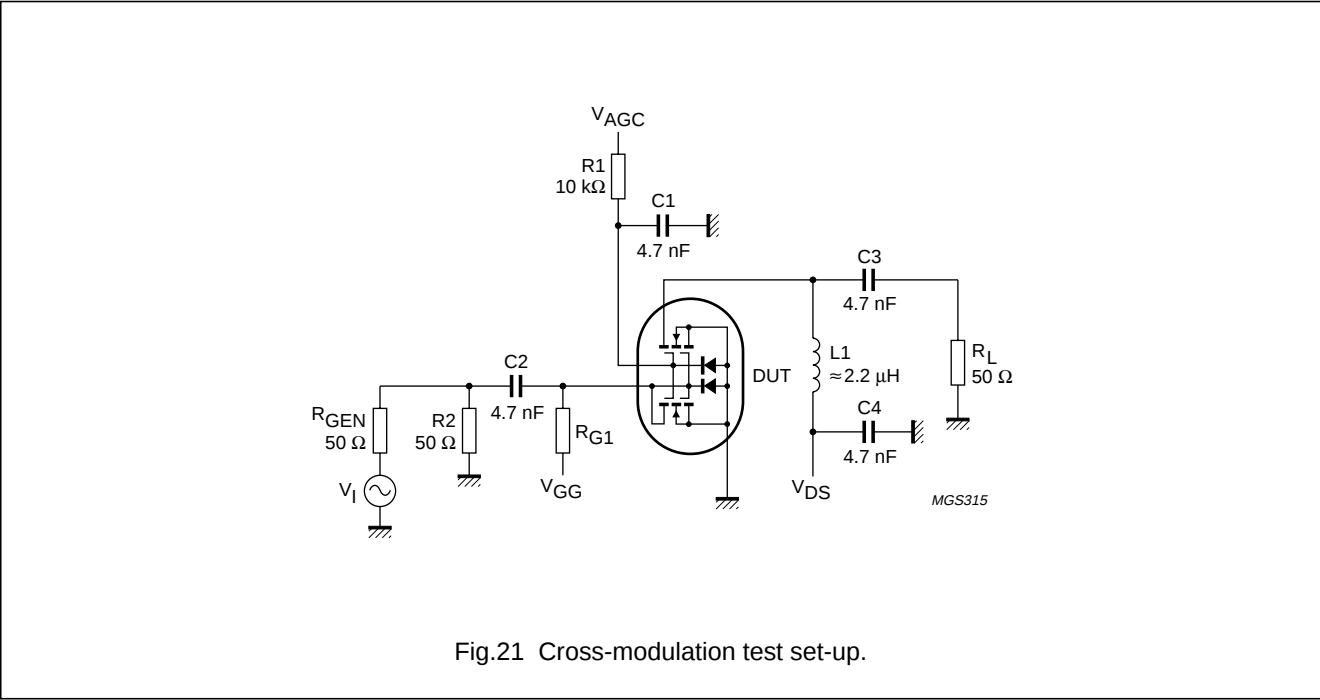


Table 1 Scattering parameters: $V_{DS} = 5\text{ V}$; $V_{G2-S} = 4\text{ V}$; $I_D = 15\text{ mA}$; $T_{amb} = 25\text{ }^{\circ}\text{C}$

f (MHz)	S ₁₁		S ₂₁		S ₁₂		S ₂₂	
	MAGNITUDE (ratio)	ANGLE (deg)	MAGNITUDE (ratio)	ANGLE (deg)	MAGNITUDE (ratio)	ANGLE (deg)	MAGNITUDE (ratio)	ANGLE (deg)
50	0.987	−4.72	2.775	174.6	0.0006	88.8	0.997	−1.84
100	0.985	−9.39	2.774	169.5	0.0010	86.7	0.997	−3.37
200	0.978	−18.59	2.731	159.1	0.0019	79.7	0.996	−6.72
300	0.976	−27.74	2.671	148.8	0.0026	74.2	0.994	−10.02
400	0.949	−36.59	2.599	138.8	0.0032	69.9	0.992	−13.33
500	0.928	−45.08	2.501	129.1	0.0035	65.9	0.989	−16.55
600	0.905	−53.26	2.400	119.8	0.0035	64.6	0.986	−19.64
700	0.882	−61.07	2.297	110.9	0.0033	65.7	0.982	−22.63
800	0.860	−68.48	2.199	102.4	0.0029	69.1	0.979	−25.54
900	0.838	−75.55	2.096	94.2	0.0024	83.3	0.975	−28.44
1000	0.818	−82.23	1.997	86.3	0.0021	103.8	0.971	−31.42

Table 2 Noise data: $V_{DS} = 5\text{ V}$; $V_{G2-S} = 4\text{ V}$; $I_D = 15\text{ mA}$; $T_{amb} = 25\text{ }^{\circ}\text{C}$

f (MHz)	F _{min} (dB)	Γ _{opt}		R _n (Ω)
		(ratio)	(deg)	
400	1	0.825	38.93	50
800	1.9	0.753	70.65	38.75

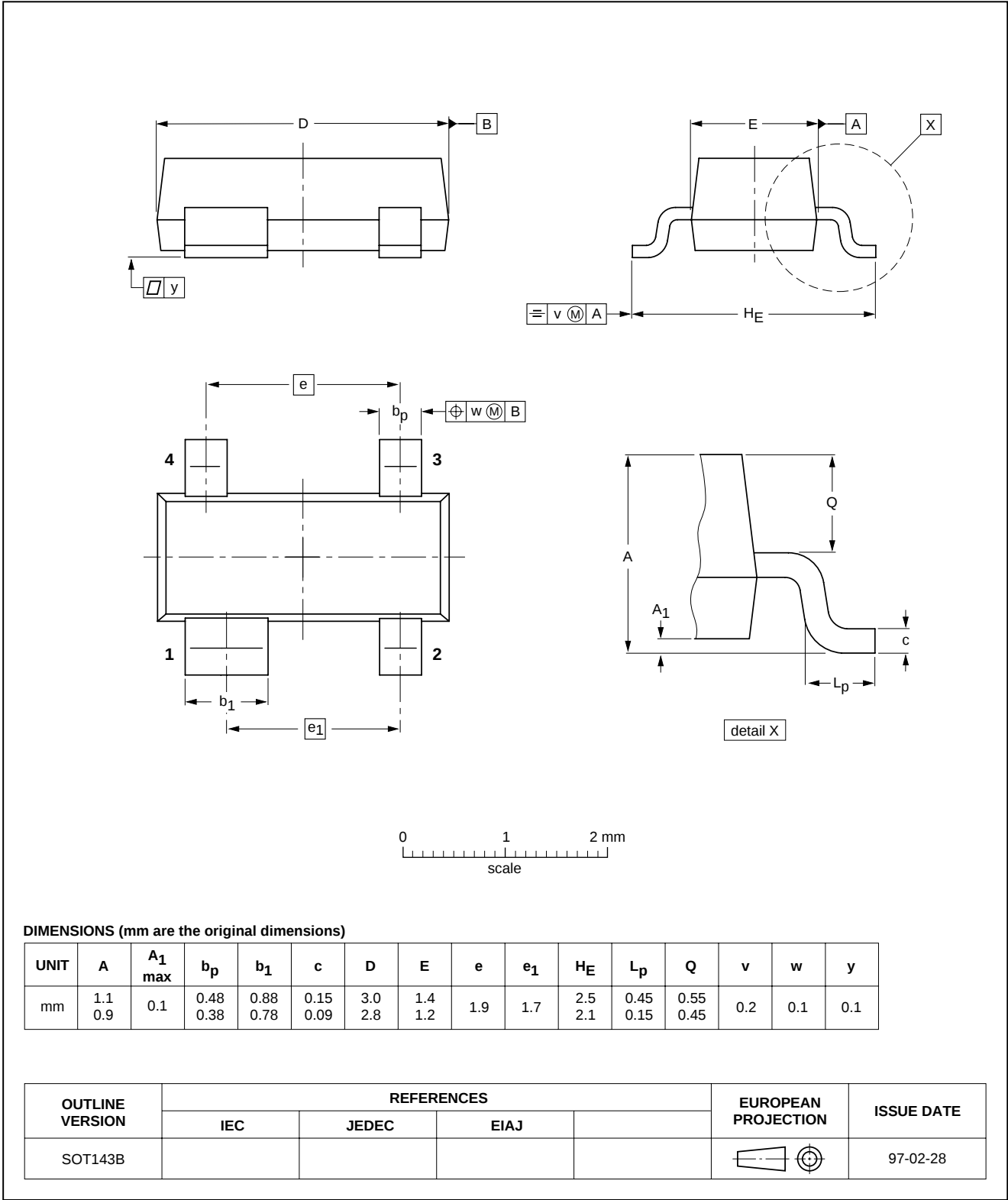
N-channel dual-gate PoLo MOS-FETs

BF1201; BF1201R;
BF1201WR

PACKAGE OUTLINES

Plastic surface mounted package; 4 leads

SOT143B

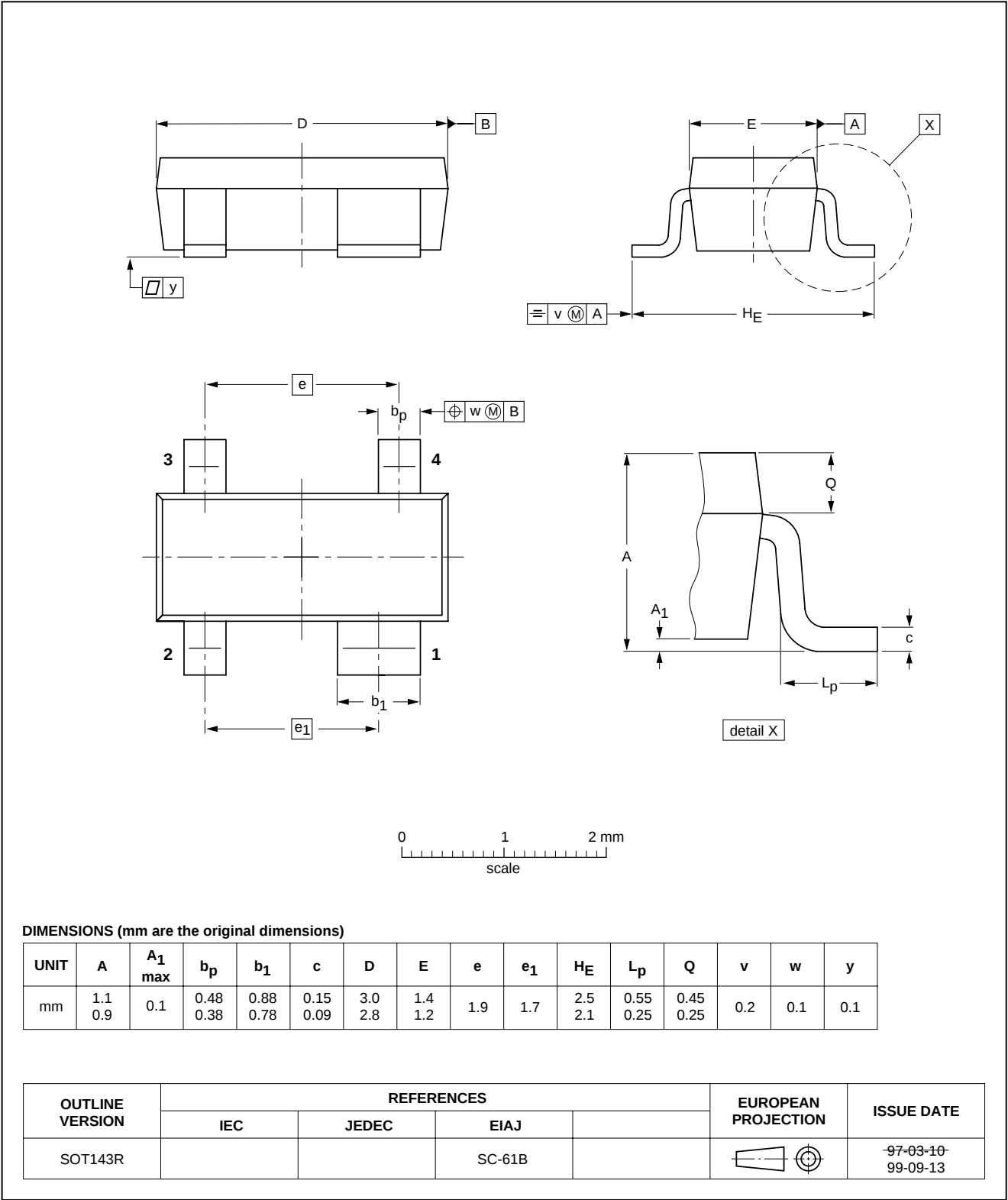


N-channel dual-gate PoLo MOS-FETs

BF1201; BF1201R;
BF1201WR

Plastic surface mounted package; reverse pinning; 4 leads

SOT143R

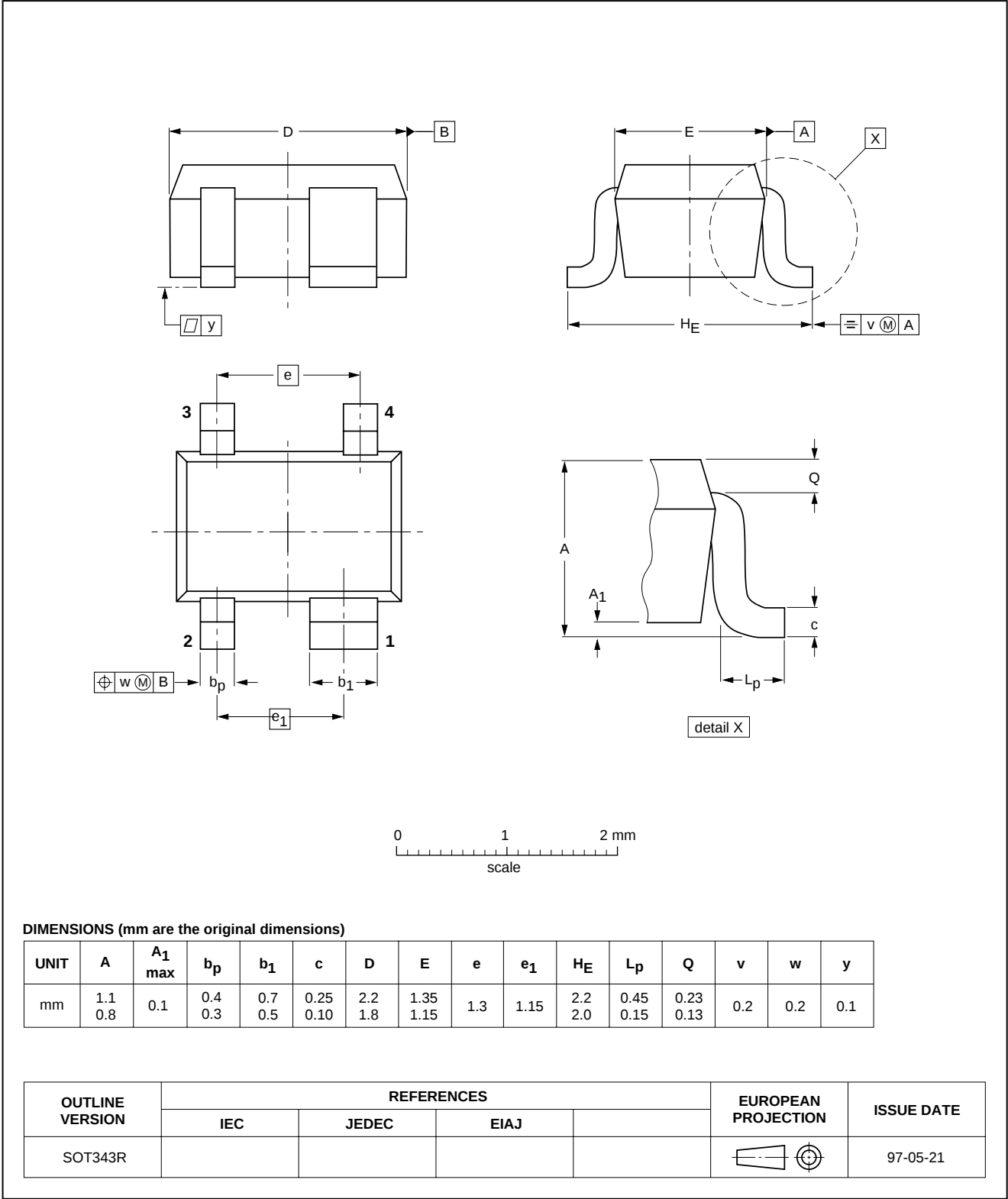


N-channel dual-gate PoLo MOS-FETs

BF1201; BF1201R;
BF1201WR

Plastic surface mounted package; reverse pinning; 4 leads

SOT343R



N-channel dual-gate PoLo MOS-FETs

BF1201; BF1201R;
BF1201WR

DATA SHEET STATUS

DATA SHEET STATUS	PRODUCT STATUS	DEFINITIONS ⁽¹⁾
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
Preliminary specification	Qualification	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product.
Product specification	Production	This data sheet contains final specifications. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product.

Note

1. Please consult the most recently issued data sheet before initiating or completing a design.

DEFINITIONS

Short-form specification — The data in a short-form specification is extracted from a full data sheet with the same type number and title. For detailed information see the relevant data sheet or data handbook.

Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 60134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

Application information — Applications that are described herein for any of these products are for illustrative purposes only. Philips Semiconductors make no representation or warranty that such applications will be suitable for the specified use without further testing or modification.

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NOTES

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NOTES

Philips Semiconductors – a worldwide company

Argentina: see South America

Australia: 3 Figtree Drive, HOMEBUSH, NSW 2140,
Tel. +61 2 9704 8141, Fax. +61 2 9704 8139

Austria: Computerstr. 6, A-1101 WIEN, P.O. Box 213,
Tel. +43 1 60 101 1248, Fax. +43 1 60 101 1210

Belarus: Hotel Minsk Business Center, Bld. 3, r. 1211, Volodarski Str. 6,
220050 MINSK, Tel. +375 172 20 0733, Fax. +375 172 20 0773

Belgium: see The Netherlands

Brazil: see South America

Bulgaria: Philips Bulgaria Ltd., Energoproject, 15th floor,
51 James Bourchier Blvd., 1407 SOFIA,
Tel. +359 2 68 9211, Fax. +359 2 68 9102

Canada: PHILIPS SEMICONDUCTORS/COMPONENTS,
Tel. +1 800 234 7381, Fax. +1 800 943 0087

China/Hong Kong: 501 Hong Kong Industrial Technology Centre,
72 Tat Chee Avenue, Kowloon Tong, HONG KONG,
Tel. +852 2319 7888, Fax. +852 2319 7700

Colombia: see South America

Czech Republic: see Austria

Denmark: Sydhavnsgade 23, 1780 COPENHAGEN V,
Tel. +45 33 29 3333, Fax. +45 33 29 3905

Finland: Sinikalliontie 3, FIN-02630 ESPOO,
Tel. +358 9 615 800, Fax. +358 9 6158 0920

France: 51 Rue Carnot, BP317, 92156 SURESNES Cedex,
Tel. +33 1 4099 6161, Fax. +33 1 4099 6427

Germany: Hammerbrookstraße 69, D-20097 HAMBURG,
Tel. +49 40 2353 60, Fax. +49 40 2353 6300

Hungary: see Austria

India: Philips INDIA Ltd, Band Box Building, 2nd floor,
254-D, Dr. Annie Besant Road, Worli, MUMBAI 400 025,
Tel. +91 22 493 8541, Fax. +91 22 493 0966

Indonesia: PT Philips Development Corporation, Semiconductors Division,
Gedung Philips, Jl. Buncit Raya Kav.99-100, JAKARTA 12510,
Tel. +62 21 794 0040 ext. 2501, Fax. +62 21 794 0080

Ireland: Newstead, Clonskeagh, DUBLIN 14,
Tel. +353 1 7640 000, Fax. +353 1 7640 200

Israel: RAPAC Electronics, 7 Kehilat Saloniki St, PO Box 18053,
TEL AVIV 61180, Tel. +972 3 645 0444, Fax. +972 3 649 1007

Italy: PHILIPS SEMICONDUCTORS, Via Casati, 23 - 20052 MONZA (MI),
Tel. +39 039 203 6838, Fax +39 039 203 6800

Japan: Philips Bldg 13-37, Kohnan 2-chome, Minato-ku,
TOKYO 108-8507, Tel. +81 3 3740 5130, Fax. +81 3 3740 5057

Korea: Philips House, 260-199 Itaewon-dong, Yongsan-ku, SEOUL,
Tel. +82 2 709 1412, Fax. +82 2 709 1415

Malaysia: No. 76 Jalan Universiti, 46200 PETALING JAYA, SELANGOR,
Tel. +60 3 750 5214, Fax. +60 3 757 4880

Mexico: 5900 Gateway East, Suite 200, EL PASO, TEXAS 79905,
Tel. +9-5 800 234 7381, Fax +9-5 800 943 0087

Middle East: see Italy

Netherlands: Postbus 90050, 5600 PB EINDHOVEN, Bldg. VB,
Tel. +31 40 27 82785, Fax. +31 40 27 88399

New Zealand: 2 Wagener Place, C.P.O. Box 1041, AUCKLAND,
Tel. +64 9 849 4160, Fax. +64 9 849 7811

Norway: Box 1, Manglerud 0612, OSLO,
Tel. +47 22 74 8000, Fax. +47 22 74 8341

Pakistan: see Singapore

Philippines: Philips Semiconductors Philippines Inc.,
106 Valero St. Salcedo Village, P.O. Box 2108 MCC, MAKATI,
Metro MANILA, Tel. +63 2 816 6380, Fax. +63 2 817 3474

Poland: Al.Jerozolimskie 195 B, 02-222 WARSAW,
Tel. +48 22 5710 000, Fax. +48 22 5710 001

Portugal: see Spain

Romania: see Italy

Russia: Philips Russia, Ul. Usatcheva 35A, 119048 MOSCOW,
Tel. +7 095 755 6918, Fax. +7 095 755 6919

Singapore: Lorong 1, Toa Payoh, SINGAPORE 319762,
Tel. +65 350 2538, Fax. +65 251 6500

Slovakia: see Austria

Slovenia: see Italy

South Africa: S.A. PHILIPS Pty Ltd., 195-215 Main Road Martindale,
2092 JOHANNESBURG, P.O. Box 58088 Newville 2114,
Tel. +27 11 471 5401, Fax. +27 11 471 5398

South America: Al. Vicente Pinzon, 173, 6th floor,
04547-130 SÃO PAULO, SP, Brazil,
Tel. +55 11 821 2333, Fax. +55 11 821 2382

Spain: Balmes 22, 08007 BARCELONA,
Tel. +34 93 301 6312, Fax. +34 93 301 4107

Sweden: Kottbygatan 7, Akalla, S-16485 STOCKHOLM,
Tel. +46 8 5985 2000, Fax. +46 8 5985 2745

Switzerland: Allmendstrasse 140, CH-8027 ZÜRICH,
Tel. +41 1 488 2741 Fax. +41 1 488 3263

Taiwan: Philips Semiconductors, 6F, No. 96, Chien Kuo N. Rd., Sec. 1,
TAIPEI, Taiwan Tel. +886 2 2134 2886, Fax. +886 2 2134 2874

Thailand: PHILIPS ELECTRONICS (THAILAND) Ltd.,
209/2 Sanpavuth-Bangna Road Prakanong, BANGKOK 10260,
Tel. +66 2 745 4090, Fax. +66 2 398 0793

Turkey: Yukari Dudullu, Org. San. Blg., 2.Cad. Nr. 28 81260 Umraniye,
ISTANBUL, Tel. +90 216 522 1500, Fax. +90 216 522 1813

Ukraine: PHILIPS UKRAINE, 4 Patrice Lumumba str., Building B, Floor 7,
252042 KIEV, Tel. +380 44 264 2776, Fax. +380 44 268 0461

United Kingdom: Philips Semiconductors Ltd., 276 Bath Road, Hayes,
MIDDLESEX UB3 5BX, Tel. +44 208 730 5000, Fax. +44 208 754 8421

United States: 811 East Arques Avenue, SUNNYVALE, CA 94088-3409,
Tel. +1 800 234 7381, Fax. +1 800 943 0087

Uruguay: see South America

Vietnam: see Singapore

Yugoslavia: PHILIPS, Trg N. Pasica 5/v, 11000 BEOGRAD,
Tel. +381 11 3341 299, Fax. +381 11 3342 553

For all other countries apply to: Philips Semiconductors,
International Marketing & Sales Communications, Building BE-p, P.O. Box 218,
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Internet: <http://www.semiconductors.philips.com>

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